

VIA EFS

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re Patent Application:	Luca Pusterla, et al.	§	
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Conf. No.:	7623	§	Group Art Unit: 1743
		§	
Appln. No.:	10/601,383	§	Examiner: Yelena G. Gakh
		§	
Filing Date:	June 23, 2003	§	Atty. Docket No.: 6023-169US
		§	(BX2453M)
Title:	METHOD FOR MEASURING THE CONCENTRATION OF IMPURITIES IN HELIUM BY ION MOBILITY SPECTROMETRY		

RESPONSE TO ELECTION OF SPECIES REQUIREMENT

This is in response to the Office Action (Election of Species requirement) dated August 22, 2006 (Paper No. 20060817). This response is being timely submitted by September 22, 2006.